Twelfth in the SPIE Critical Reviews of Technology Series

Proceedings of SPIE—The International Society for Optical Engineering

Volume 532

Holography

Lloyd Huff Chairman/Editor

January 24-25, 1985 Los Angeles, California

An SPIE Critical Reviews of Technology conference brings together an invited group of experts in a selected technology. Each presents an extended critical review paper that characterizes the state of the art of the technology by assessing key developments from past research and identifying important areas of current work. The conference is designed to present an overview of the technology and to result in a proceedings of value to individuals working in this or related technologies.

Published by

SPIE—The International Society for Optical Engineering
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone 206/676-3290 (Pacific Time) • Telex 46-7053

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